ELEC-E4130

Lecture 16: Multilayer (Stratified Media) Beam splitter for a two arm interferometer



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Interferometer (wikipedia)





- Interference of light with advanced/delayed copies of itself achieved via splitting light into two arms, modulating the path of one arm while keeping the second arm stationary, recombining light at a detector
- Analysis of interference allows for
 - > Determination of light spectrum of is path lengths are well known
 - Determination of sample or mirror spectral response (both source and paths are known)
- Also see Michelson–Morley experiment



Interferometer (Bruker)



- Interferometers at very long wave IR (sometimes known as submillimeter wave, 100 GHz 1 THz) often use self supporting dielectric beam splitters to divide and recombine the beam
- Self supporting dielectric beam splitter means a thin, dielectric film suspended from a ring with no supporting structure
- > Lets use multilayer calculations to design a beam splitter for a particular frequency band



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IN 2

IN 1

→ OUT 1

→ OUT 3

OF

Sources















$$I_{tot} = E_{tot}^* E_{tot} = 2|E_0|^2 |\Gamma|^2 |\Gamma|^2 (1 + \cos(2k\Delta d))$$

- The total received signal will be modified by the power reflection and transmission of the dielectric thin film beam splitter
- Assuming no loss in the beam splitter, How do we maximize signal?

$$R_0 = |\Gamma|^2$$

 $R_0 + T_0 = 1$
 $T_0 = |T|^2$

$$\mathbf{R}_0 T_0 = \mathbf{R}_0 \left(1 - \mathbf{R}_0 \right)$$

$$\frac{d}{dR_0} R_0 \left(1 - R_0 \right) = 0 \longrightarrow R_0 = 0.5$$

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Maximum signal occurs when power reflectivity and power transmissivity are equal



Oblique Incidence: Single slab



$$\rho_{T,2} = \frac{n_{T,1} - n_{T,b}}{n_{T,1} + n_{T,b}} \qquad \tau_{T,2} = 1 + \rho_{T,2}$$

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Optical path



$$\left|\frac{\rho_{T,1} + \rho_{T,2} e^{-j2\delta_m}}{1 + \rho_{T,1}\rho_{T,2} e^{-j2\delta_m}}\right|^2 = \left|\frac{\tau_{T,1}\tau_{T,2} e^{-j\delta_m}}{1 + \rho_{T,1}\rho_{T,2} e^{-j2\delta_m}}\right|^2$$

Find the correct thickness and refractive index for a given wavelength





Nulls

$$\delta_{\rm m} = {\rm k}_{\rm m} \ell_{\rm m} \cos(\theta_m) = n\pi$$

Peaks

$$\delta_{\rm m} = k_{\rm m} \ell_{\rm m} \cos(\theta_m) = \frac{n}{2} \pi$$

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